

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re application of: Deok-Yong KIM, et al.

Serial No.: 10/749,670 Examiner: Rosario, Dennis

Filed: December 30, 2003 Group Art Unit: 2624

Confirmation No.: 9761

For: METHOD AND APPARATUS FOR DETECTING DEFECTS ON A  
WAFER

Mail Stop Amendment  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**AMENDMENT**

Responsive to the Office Action, Paper No. 20070518, dated May 31, 2007, please  
amend the application as follows.

- **Amendments to the Specification** begin on page 2 of this paper.
- **Amendments to the Claims** are reflected in the listing of claims which begins on page 3 of this paper.
- **Remarks/Arguments** begin on page 7 of this paper.